

Amendments to the Claims:

Please cancel claims 1-20. Please add new claims 21-40.

The claims are as follows:

1-20 (Cancelled)

21. (New) An electrical structure, comprising:

a parent terrain denoted as V_0 ; and

N voltage islands denoted as V_1, V_2, \dots, V_N nested within said parent terrain, N at least 2, voltage island V_Z nested within a voltage island V_{Z-1} for $Z=1, 2, \dots, N$.

22. (New) The electrical structure of claim 21, wherein each voltage island of the N voltage islands includes one or more voltage power supplies selected from the group consisting of an internal voltage island VDDI power supply, an externally supplied state saving VDDSS power supply, an externally supplied VDDN power supply, and combinations thereof.

23. (New) The electrical structure of claim 22, wherein said one or more power supplies of voltage island V_X for $X=1, 2, \dots, N$ are each independently coupled to one of (a) said one or more power supplies of voltage island V_Y , for $Y=1, 2, \dots, N$, X not equal to Y , (b) a VDDO power supply of said parent terrain or (c) one or more external to said parent terrain power supplies.

24. (New) The electrical structure of claim 21, wherein each voltage island of the N voltage islands includes (a) an externally supplied VDDN power supply and a voltage shifting means, or

(b) said externally supplied VDDN power supply and a fencing means, or (c) said externally supplied VDDN power supply, said voltage shifting means and said fencing means.

25. (New) The electrical structure of claim 24, wherein said fencing means comprises logic latches.

26. (New) The electrical structure of claim 24, wherein each voltage island of the N voltage islands further includes one or more substructures selected from the group consisting of (a) an internal voltage island VDDI power distribution network, (b) state saving means, (c) one or more switching elements coupled between said externally supplied VDDN power supply and said internal voltage island VDDI power distribution network, and (d) one or more voltage buffering circuits.

27. (New) The electrical structure of claim 26, wherein said one or more switching elements is selected from the group consisting of hard connections, voltage regulators, headers and footers.

28. (New) The electrical structure of claim 26, wherein said state saving means includes at least one state saving latch.

29. (New) The electrical structure of claim 21, wherein one or more voltage islands of the N voltage islands further includes a power management state machine coupled to an internal voltage island VDDI power supply distribution network, said power management state machine

of voltage island V_X for $X=1, 2, \dots, N$ located in (a) voltage island V_Y for $Y=1, 2, \dots, N$, Y less than X , or (b) in said parent terrain.

30. (New) The electrical structure of claim 21, wherein said parent terrain is an integrated circuit chip or a voltage island within said integrated circuit chip.

31. (New) A method, comprising:

providing a parent terrain denoted as V_0 ; and

nesting N voltage islands denoted as V_1, V_2, \dots, V_N within said parent terrain, N at least 2, voltage island V_Z nested within a voltage island V_{Z-1} for $Z=1, 2, \dots, N$.

32. (New) The method of claim 31, wherein each voltage island of the N voltage islands includes one or more voltage power supplies selected from the group consisting of an internal voltage island VDDI power supply, an externally supplied state saving VDDSS power supply, an externally supplied VDDN power supply, and combinations thereof.

33. (New) The method of claim 32, wherein said one or more power supplies of voltage island V_X for $X=1, 2, \dots, N$ are each independently coupled to one of (a) said one or more power supplies of voltage island V_Y , for $Y=1, 2, \dots, N$, X not equal to Y , (b) a VDDO power supply of said parent terrain or (c) one or more external to said parent terrain power supplies.

34. (New) The method of claim 31, wherein each voltage island of the N voltage islands includes (a) an externally supplied VDDN power supply and a voltage shifting means, or (b) said

externally supplied VDDN power supply and a fencing means, or (c) said externally supplied VDDN power supply, said voltage shifting means and said fencing means.

35. (New) The method of claim 34, wherein said fencing means comprises logic latches.

36. (New) The method of claim 34, wherein each voltage island of the N voltage islands further includes one or more substructures selected from the group consisting of (a) an internal voltage island VDDI power distribution network, (b) state saving means, (c) one or more switching elements coupled between said externally supplied VDDN power supply and said internal voltage island VDDI power distribution network, and (d) one or more voltage buffering circuits.

37. (New) The method of claim 36, wherein said one or more switching elements is selected from the group consisting of hard connections, voltage regulators, headers and footers.

38. (New) The method of claim 36, wherein said state saving means includes at least one state saving latch.

39. (New) The method of claim 31, wherein one or more voltage islands of the N voltage islands further includes a power management state machine coupled to an internal voltage island VDDI power supply distribution network, said power management state machine of voltage island V_x for $X=1, 2, \dots, N$ located in (a) a voltage island V_Y for $Y=1, 2, \dots, N$, Y less than X , or (b) in said parent terrain.

40. (New) The method of claim 31, wherein said parent terrain is an integrated circuit chip or a voltage island within said integrated circuit chip